

<b>Notice of References Cited</b>		Application/Control No. 10/542,663	Applicant(s)/Patent Under Reexamination INUI ET AL.	
		Examiner ANKUSH k. SINGAL	Art Unit 2823	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,388,386 B1	05-2002	Kunii et al.	315/169.3
*	B	US-2003/0153182 A1	08-2003	Yamazaki et al.	438/689
*	C	US-2004/0084679 A1	05-2004	Nakayama, Junichiro	257/075
*	D	US-2004/0087116 A1	05-2004	Nakayama, Junichiro	438/487
*	E	US-2004/0106241 A1	06-2004	Kim et al.	438/166
*	F	US-2004/0235230 A1	11-2004	Inui et al.	438/200
*	G	US-2005/0040412 A1	02-2005	Kokubo et al.	257/085
*	H	US-2005/0064675 A1	03-2005	Kim, Young-Joo	438/401
*	I	US-2005/0098784 A1	05-2005	Isobe et al.	257/066
*	J	US-2005/0161742 A1	07-2005	Isobe et al.	257/347
*	K	US-7,011,911 B2	03-2006	Kim et al.	430/5
*	L	US-2006/0125120 A1	06-2006	Kim, Young-Joo	257/797
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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